Results

NOTE: this is the SOLUTION to Quiz 1.

The correct answers are indicated for each question, with explanations as needed.

Dr. Manikas

Your Answers:

1 4/4 points

Classes of architectural parallelism include:

Data-Level Parallelism (DLP)

Task-Level Parallelism (TLP)

Thread-Level Parallelism

Instruction-Level Parallelism (ILP)

Feedback

General Feedback

- Classes of parallelism in applications:
 - Data-Level Parallelism (DLP)
 - Task-Level Parallelism (TLP)
- Classes of architectural parallelism:
 - Instruction-Level Parallelism (ILP)

4/4 points

Classes of parallelism in applications include:

- Thread-Level Parallelism
- Instruction-Level Parallelism (ILP)
- ▼ Task-Level Parallelism (TLP)

✓ Data-Level Parallelism (DLP)

Feedback

General Feedback

- Classes of parallelism in applications:
 - Data-Level Parallelism (DLP)
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- Classes of architectural parallelism:
 - Instruction-Level Parallelism (ILP)
 - Thread-Level Parallelism

4/4 points

Your design team wishes to manufacture a new microprocessor, with a codename of "Peruna". The chip has a die size of 400 mm². Your manufacturing facility makes wafers that are 500 mm in diameter. How many Peruna dies can you get from one wafer?



435

Feedback

General Feedback

$$DiesPerWafer = rac{\pi [rac{WaferDiameter}{2}]^2}{DieArea} - rac{\pi (WaferDiameter)}{\sqrt{2(DieArea)}}$$

Plugging in our values, we get:

$$DiesPerWafer = rac{\pi [rac{500}{2}]^2}{400} - rac{\pi (500)}{\sqrt{2(400)}}$$

$$DiesPerWafer = \pi [rac{250^2}{400} - rac{500}{\sqrt{800}}] = 138.572\pi$$

This rounds down to 435 dies per wafer, since we are interested in producing complete dies.

4

4/4 points

Your design team wishes to manufacture a new microprocessor, with a codename of "Mustang". The chip has a die size of 500 mm², with an estimated defect rate of 0.02/cm². Your manufacturing facility has process-complexity factor of 10, and we are assuming a wafer yield of 100%. What is the **yield** for the Mustang chip?



0.386

Feedback

General Feedback

Recall that we can calculate die yield using the following equation:

$$DieYield = rac{WaferYield}{\left(1 + \left(DefectsPerUnitArea
ight)\left(DieArea
ight)
ight)^{N}}$$

Then we have:

Wafer yield = 100% = 1

Defects per unit area = 0.02/cm²

Die area = 500 mm^2

Process-complexity factor N = 10

Need to convert area so that units match: 1 cm = 10 mm, so $(1 \text{ cm})^2 = (10 \text{ mm})^2$, or $1 \text{ cm}^2 = 100 \text{ mm}^2$

$$DefectsPerUnitArea = rac{0.02}{cm^2} [rac{cm^2}{100mm^2}] = rac{0.02}{100mm^2}$$

Now we can plug everything into the equation:

$$DieYield = rac{1}{(1+(rac{0.02}{100})(500))^{10}} = rac{1}{(1+0.1)^{10}} = 0.386$$

5

4/4 points

Your design team wishes to manufacture a new microprocessor, with a codename of "Maverick". Your manufacturing facility can produce 1000 Maverick dies per wafer, with a die yield of 0.625. Each defect-free Maverick chip makes a profit of \$10. How much profit will you make on each wafer of Maverick chips (\$)?



6,250

Feedback

General Feedback

Profit = (dies per wafer)(die yield)(profit per defect-free chip)

We are given the number of complete dies per wafer is 1000. and the die yield is 0.625 (percentages of *defect-free* dies per wafer).

Thus the profit per wafer becomes (1000)(0.625)(\$10) = \$6250